

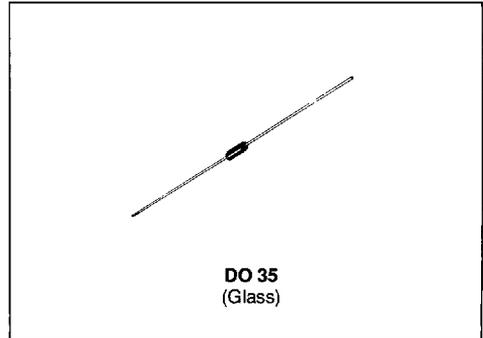

**SGS-THOMSON**  
 MICROELECTRONICS

 T-11-09  
**1N 4775, A → 1N 4784, A**

S G S-THOMSON

**TEMPERATURE COMPENSATED ZENER DIODES**
**NEW SERIE**

- SEMICONDUCTOR MATERIAL : SILICON
- TECHNOLOGY : LOCAL EPITAXY + GUARD RING


**ABSOLUTE RATINGS** (limiting values)

Symbol	Parameter	Value	Unit
$P_{tot}$	Power Dissipation* $T_{amb} = 50^{\circ}\text{C}$	0.4	W
$T_{stg}$ $T_J$	Storage and Junction Temperature Range	- 65 to 175 - 65 to 175	$^{\circ}\text{C}$ $^{\circ}\text{C}$
$T_L$	Maximum Lead Temperature for Soldering during 10s at 4mm from Case	230	$^{\circ}\text{C}$

**THERMAL RESISTANCE**

Symbol	Parameter	Value	Unit
$R_{th(j-a)}$	Junction to Ambient*	300	$^{\circ}\text{C}/\text{W}$

**ELECTRICAL CHARACTERISTICS** ( $T_{amb} = 25^{\circ}\text{C}$  unless otherwise specified)

Types	$V_{ZT}$ typ. (V)	$R_{ZT}$ @ $I_{ZT}$ max. ( $\Omega$ ) (mA)		Test Temperatures ( $^{\circ}\text{C}$ )			$\Delta V_Z^{**}$ max. (mV)	$\alpha V_Z$ ( $10^{-6}/^{\circ}\text{C}$ )
1N 4775	8.5	200	0.5	0	+ 25	+ 75	64	100
1N 4776	8.5	200	0.5	0	+ 25	+ 75	32	50
1N 4777	8.5	200	0.5	0	+ 25	+ 75	13	20
1N 4778	8.5	200	0.5	0	+ 25	+ 75	6	10
1N 4779	8.5	200	0.5	0	+ 25	+ 75	3	5
1N 4775 A	8.5	200	0.5	- 55	0	+ 25 + 75 + 100	132	100
1N 4776 A	8.5	200	0.5	- 55	0	+ 25 + 75 + 100	66	50
1N 4777 A	8.5	200	0.5	- 55	0	+ 25 + 75 + 100	26	20
1N 4778 A	8.5	200	0.5	- 55	0	+ 25 + 75 + 100	13	10
1N 4779 A	8.5	200	0.5	- 55	0	+ 25 + 75 + 100	7	5

\* On infinite heatsink with  $d = 4\text{mm}$ .\*\* The voltage reference diodes are characterized by the box method. The maximum allowable voltage change  $\Delta V_Z$  is guaranteed any two temperature within the range. Tests are performed at the indicated temperatures and the specified current.

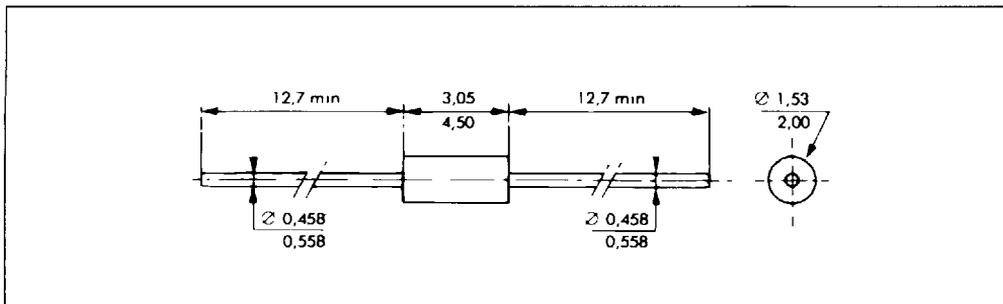
## ELECTRICAL CHARACTERISTICS (continued)

Types	$V_{ZT}$ typ. (V)	$R_{ZT}$ @ $I_{ZT}$		Test Temperatures			$\Delta V_{Z}^{**}$ max. (mV)	$\alpha V_Z$ ( $10^{-6}/^{\circ}\text{C}$ )
		max. ( $\Omega$ )	(mA)	( $^{\circ}\text{C}$ )				
1N 4780	8.5	100	1	0	+ 25	+ 75	64	100
1N 4781	8.5	100	1	0	+ 25	+ 75	32	50
1N 4782	8.5	100	1	0	+ 25	+ 75	13	20
1N 4783	8.5	100	1	0	+ 25	+ 75	6	10
1N 4784	8.5	100	1	0	+ 25	+ 75	3	5
1N 4780 A	8.5	100	1	- 55	0	+ 25 + 75 + 100	132	100
1N 4781 A	8.5	100	1	- 55	0	+ 25 + 75 + 100	66	50
1N 4782 A	8.5	100	1	- 55	0	+ 25 + 75 + 100	26	20
1N 4783 A	8.5	100	1	- 55	0	+ 25 + 75 + 100	13	10
1N 4784 A	8.5	100	1	- 55	0	+ 25 + 75 + 100	7	5

\* The voltage reference diodes are characterized by the box method. The maximum allowable voltage change  $\Delta V_Z$  is guaranteed any two temperature within the range.

## PACKAGE MECHANICAL DATA

DO 35 Glass



Cooling method by convection and conduction.

Marking . clear, ring at cathode end.

Weight 0.15g

## S G S-THOMSON

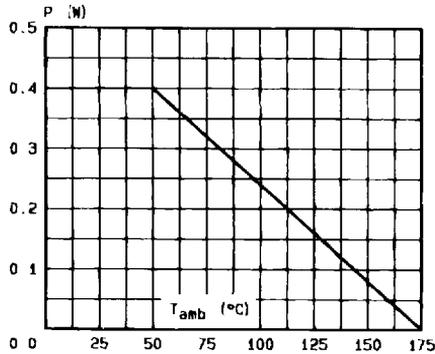


Fig 1 - Power dissipation versus ambient temperature.

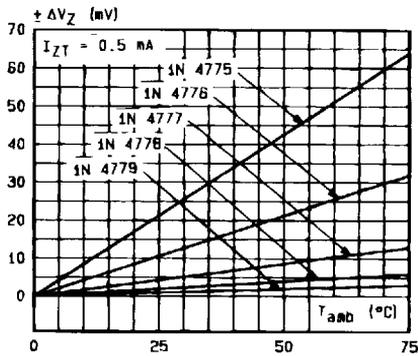


Fig 2a - Regulation voltage variation versus ambient temperature.

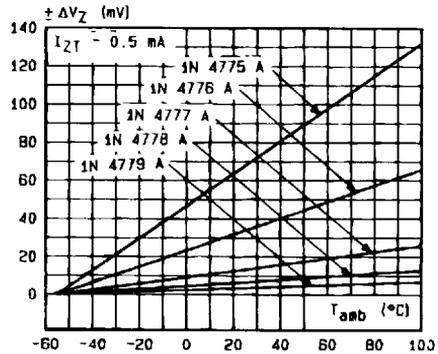


Fig 2b - Regulation voltage variation versus ambient temperature.

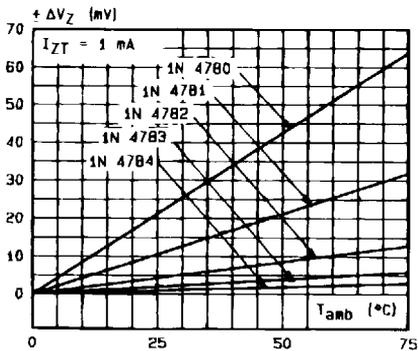


Fig 2c - Regulation voltage variation versus ambient temperature

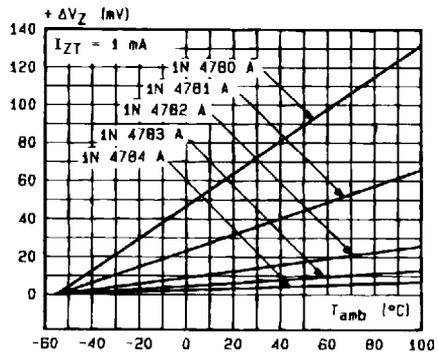


Fig 2d - Regulation voltage variation versus ambient temperature